

## 1. Product information

Supplier : JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO.,LTD.

|                       |                  |
|-----------------------|------------------|
| <b>Part Number :</b>  | CJAB55N03S       |
| <b>Package Type :</b> | PDFNWB3.3x3.3-8L |
| <b>Report Date:</b>   | March-2026       |

## 2. Reference Standard

| Item                  | Standards   |
|-----------------------|-------------|
| 1.Human Man Body(HBM) | JESD22-A114 |
| 2.Machine Model(MM)   | JESD22-A115 |

## 3. Classification Criteria

| HBM Classification levels |  |
|---------------------------|--|
| Level                     | Test voltage                               |
| Class 0                   | $\leq 250 \text{ V}$                       |
| Class 1A                  | $> 250 \text{ V to } \leq 500 \text{ V}$   |
| Class 1B                  | $> 500 \text{ V to } \leq 1000 \text{ V}$  |
| Class 1C                  | $> 1000 \text{ V to } \leq 2000 \text{ V}$ |
| Class 2                   | $> 2000 \text{ V to } \leq 4000 \text{ V}$ |
| Class 3A                  | $> 4000 \text{ V to } \leq 8000 \text{ V}$ |
| Class 3B                  | $> 8000 \text{ V}$                         |

| MM Classification levels |  |
|--------------------------|--|
| Level                    | Test voltage                             |
| Class A                  | $< 200 \text{ V}$                        |
| Class B                  | $\geq 200 \text{ V to } < 400 \text{ V}$ |
| Class C                  | $\geq 400 \text{ V}$                     |

## 4. Test Result

| Test item | Test Condition                                    | Samples | Class Level |
|-----------|---|---------|-------------|
| HBM       | interval:1s 3Times /200V~8000V step:200V( $\pm$ ) | 5PCS    | CLASS 1C    |
| MM        | Interval 1s 3Times /200V~800V step:200V( $\pm$ )  | 5PCS    | CLASS B     |

### Notes:

The failure criterion for the ESD test is based on whether the Device Under Test (DUT) meets its product specification (datasheet). Specifically, after being subjected to the specified ESD pulse stress, the device must undergo electrical parameter testing and functional checks. The device shall be considered failed if any of the following conditions occur:

- 1) Electrical parameters deviate from the limits specified in the datasheet;
- 2) Logic functions or preset functions cannot be realized.

Remark: JSCJ Laboratory reserves the right of final interpretation of this report